Abstracts

Analysis of Shielded Coplanar Waveguide Step Discontinuity Considering the Finite Metallization Thickness Effect

C.-W. Kuo, T. Kitazawa and T. Itoh. "Analysis of Shielded Coplanar Waveguide Step Discontinuity Considering the Finite Metallization Thickness Effect." 1991 MTT-S International Microwave Symposium Digest 91.2 (1991 Vol. II [MWSYM]): 473-475.

The mode-matching technique is applied to analyze the shielded coplanar waveguide (CPW) step discontinuity. Effect of the finite thickness of the CPW center strip and ground planes is also considered. Results of the frequency-dependent scattering parameters of the shielded CPW step discontinuity incorporating the finite metallization thickness effect are presented for the first time.

❑ Return to main document.